- Fixed 3.3-V Output
- ±1% Maximum Output Voltage Tolerance at T_J = 25°C
- 500-mV Maximum Dropout Voltage at 500 mA
- 500-mA Dropout Current
- ±2% Absolute Output Voltage Variation
- Internal Overcurrent Limiting
- Internal Thermal-Overload Protection
- Internal Overvoltage Protection
- Package Options Include Plastic Flange Mounted (KTP), Power (KC), and Thin Shrink Small-Outline (PW) Packages, and Ceramic Chip Carriers (FK) and DIPs (J)

description

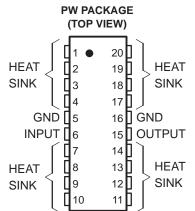
The TLV2217-33 is a low-dropout 3.3-V fixedvoltage regulator. The regulator is capable of sourcing 500 mA of current with an input-output differential of 0.5 V or less. The TLV2217-33 provides internal overcurrent limiting, thermaloverload protection, and overvoltage protection.

The 0.5-V dropout for the TLV2217-33 makes it ideal for battery applications in 3.3-V logic systems. For example, battery input voltage to the regulator can drop as low as 3.8 V, and the TLV2217-33 can continue to regulate the system. For higher voltage systems, the TLV2217-33 can be operated with a continuous input voltage of 12 V.

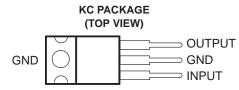
The TLV2217-33 regulators are characterized for operation from 0°C to 125°C virtual junction temperature.

The TLV2217-33M regulators are characterized for operation over the full military virtual junction temperature range of -55° C to 125° C.

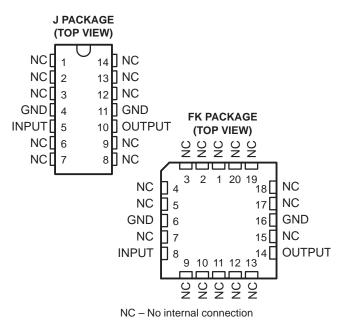


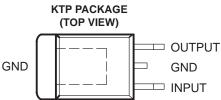


HEAT SINK – These terminals have an internal resistive connection to ground and should be grounded or electrically isolated.



The GND terminal is in electrical contact with the mounting base.





The GND terminal is in electrical contact with the mounting base.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

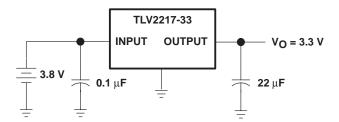
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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application schematic



AVAILABLE OPTIONS

	PACKAGED DEVICES					
Тј	CHIP CARRIER (FK)	CERAMIC DIP (J)	PLASTIC POWER (KC)	SURFACE MOUNT (PW) [†]	PLASTIC FLANGE MOUNT (KTP) [†]	CHIP FORM (Y)
0°C to 125°C	—	—	TLV2217-33KC	TLV2217-33PWR	TLV2217-33KTPR	TLV2217-33Y
–55°C to 125°C	TLV2217-33MFKB	TLV2217-33MJB	—	—	—	1202217-331

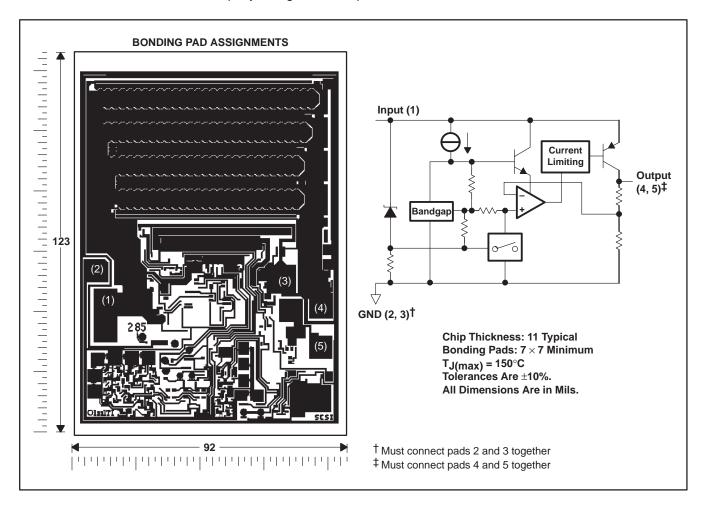
[†] The KTP and PW packages are available left-end taped and reeled only.



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TLV2217-33Y chip information

These chips, when properly assembled, display characteristics similar to the TLV2217-33 (see electrical tables). Thermal compression or ultrasonic bonding can be used on the doped aluminum bonding pads. The chip can be mounted with conductive epoxy or a gold-silicon preform.





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absolute maximum ratings over operating virtual junction temperature range (unless otherwise noted) $\!\!\!\!^\dagger$

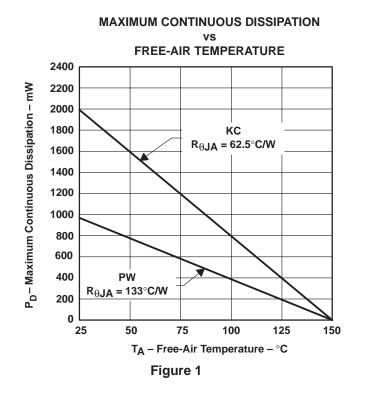
Continuous input voltage, V _I
Continuous total power dissipation (see Note 1) See Dissipation Rating Table
Storage temperature range, T _{stg} –65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: J package
KC or PW package 260°C

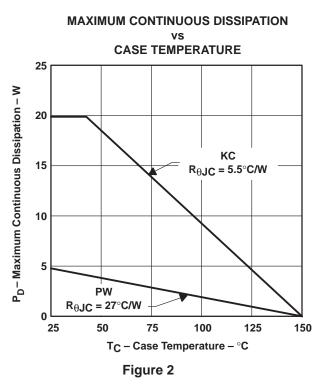
[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: Refer to Figures 1 and 2 to avoid exceeding the design maximum virtual junction temperature; these ratings should not be exceeded. Due to variation in individual device electrical characteristics and thermal resistance, the built-in thermal overload protection may be activated at power levels slightly above or below the rated dissipation.

DISSIPATION RATING TABLE								
PACKAGE	POWER RATING AT	$\textbf{T} \leq \textbf{25}^\circ\textbf{C}$ POWER RATING	DERATING FACTOR ABOVE T = 25°C	T = 70°C POWER RATING	T = 85°C POWER RATING	T = 125°C POWER RATING		
FK	T _A	1375 mW	11 mW/°C	880 mW	715 mW	275 mW		
J	TA	1375 mW	11 mW/°C	880 mW	715 mW	275 mW		
KC	TA	2000 mW	16 mW/°C	1280 mW	1040 mW	400 mW		
KC	т _С ‡	20000 mW	182 mW/°C	14540 mW	11810 mW	4530 mW		
PW	TA	950 mW	7.6 mW/°C	608 mW	494 mW	190 mW		
FVV	т _С	4625 mW	37 mW/°C	2960 mW	2405 mW	925 mW		
KTP	TA	1800 mW	14.5 mW/°C	1147 mW	943 mW	363 mW		
NIF	т _С ‡	18000 mW	163.6 mW/°C	13091 mW	10636 mW	4091 mW		

[‡] Derate above 40°C







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TLV2217-33 recommended operating conditions

	TLV2217-33 MIN MAX		UNIT
			UNIT
Input voltage, VI	3.8	12	V
Output current, IO	0	500	mA
Operating virtual junction temperature range, TJ	0	125	°C

TLV2217-33M recommended operating conditions

		٦	TLV2217-33M		UNIT
			MIN	MAX	UNIT
	$T_J = 25^{\circ}C$		3.8	12	V
Input voltage, V _I	$T_J = -55^{\circ}C$ to $125^{\circ}C$		3.9	МАХ	V
Output current, IO			0	480	mA
Operating virtual junction temperature	range, TJ		-55	125	°C

electrical characteristics at V_I = 4.5 V, I_O = 500 mA, T_J = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS [†]			TLV2217-33		
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
Output weltere	$I_{O} = 20 \text{ mA to } 500 \text{ mA},$		$T_J = 25^{\circ}C$	3.267	3.30	3.333	V
Output voltage	10 = 20 mA to 500 mA,	V = 3.8 V 10 5.5 V	$T_J = 0^{\circ}C$ to $125^{\circ}C$	3.234		3.366	v
Input voltage regulation	VI = 3.8 V to 5.5 V				5	15	mV
Ripple rejection	f = 120 Hz,	V _{ripple} = 1 V _{PP}			-62		dB
Output voltage regulation	I_{O} = 20 mA to 500 mA				5	30	mV
Output noise voltage	f = 10 Hz to 100 kHz				500		μV
Dropoutvoltogo	IO = 250 mA					400	mV
Dropout voltage	IO = 500 mA					500	mv
Bias current	IO = 0				2	5	mA
	IO = 500 mA				19	49	ША

[†] Pulse-testing techniques are used to maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 22-μF tantalum capacitor with equivalent series resistance of 1.5 Ω on the output.



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electrical characteristics at V_I = 4.5 V, I_O = 500 mA, T_J = 25°C (unless otherwise noted)

PARAMETER	_	TEST CONDITIONS [†]			TLV2217-33M		
PARAMETER	I I	EST CONDITIONS		MIN	TYP	3M MAX 3.333 3.366 15 30 30 400 550	UNIT
Output voltage	$l_{0} = 20 \text{ m/s} + 0.490 \text{ m/s}$	V _I = 3.8 V to 5.5 V,	$T_J = 25^\circ$	3.267	3.3	3.333	V
Output voltage	$I_{O} = 20 \text{ mA to } 480 \text{ mA}$	VI = 3.9 V to 5.5 V		3.234		3.366	v
Input voltage regulation	V _I = 3.8 V to 5.5 V,	TJ = 25°C				15	mV
Ripple rejection	f = 120 Hz,	V _{ripple} = 1 V _{PP}			-62		dB
Output voltage regulation	$I_{O} = 20 \text{ mA to } 480 \text{ mA},$	T _J = 25°C				30	mV
Output noise voltage	f = 10 Hz to 100 kHz				500		μV
	I _O = 250 mA					400	
Dropout voltage	I _O = 480 mA,	T _J = 25°C				500	mV
	I _O = 480 mA					550	
Dino ourrent	IO = 0			MIN TYP MAX 3.267 3.3 3.333 3.234 3.366 -62 15 -62 30 500 400 500 500	5	A	
Bias current	I _O = 480 mA			4			mA

[†] Pulse-testing techniques are used to maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 22-μF tantalum capacitor with equivalent series resistance of 1.5 Ω on the output.

electrical characteristics at V_I = 4.5 V, I_O = 500 mA, T_J = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS [†]			TLV2217-33Y		
PARAMETER	TESTC	CONDITIONS	MIN	TYP	MAX	UNIT	
Output voltage	$I_{O} = 20 \text{ mA to } 500 \text{ mA},$	$V_{I} = 3.8 \text{ V to } 5.5 \text{ V}$	3.267	3.30	3.333	V	
Input voltage regulation	$V_{I} = 3.8 \text{ V to } 5.5 \text{ V}$			5	15	mV	
Ripple rejection	f = 120 Hz,	V _{ripple} = 1 V _{PP}		-62		dB	
Output voltage regulation	I _O = 20 mA to 500 mA			5	30	mV	
Output noise voltage	f = 10 Hz to 100 kHz			500		μV	
Deservationality and	I _O = 250 mA				400	mV	
Dropout voltage	I _O = 500 mA				500	mv	
Bias current	$I_{O} = 0$			2	5	mA	
	I _O = 500 mA			19	49	ШA	

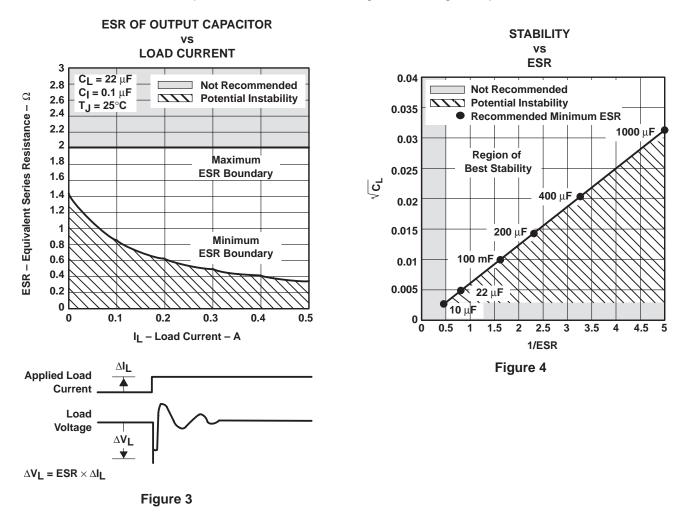
[†] Pulse-testing techniques are used to maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 22-μF tantalum capacitor with equivalent series resistance of 1.5 Ω on the output.



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COMPENSATION CAPACITOR SELECTION INFORMATION

The TLV2217-33 is a low-dropout regulator. This means that the capacitance loading is important to the performance of the regulator because it is a vital part of the control loop. The capacitor value and the equivalent series resistance (ESR) both affect the control loop and must be defined for the load range and the temperature range. Figures 3 and 4 can be used to establish the capacitance value and ESR range for best regulator performance.





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